

Notice of References Cited

Application/Control No.

10/591,475

Applicant(s)/Patent Under

Reexamination

TAKASHIMA ET AL.

Examiner

Mark L. Shevin

Art Unit

1793

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0179207	12-2002	Koike et al.	148/648
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K	US-			
L	US-			
M	US-			

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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